

Appl. no. 10/815,400
IDS dated June 1, 2009

Modified Form PTO/SB/08A

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| Substitute for form 1449/APTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary) | <i>Complete If Known</i> | |
| | Application Number | 10/815,400 |
| | First Named Inventor | Eldridge et al. |
| | Filing Date | March 31, 2004 |
| | Group Art Unit | 2829 |
| | Examiner Name | Ernest F. Karlson |
| No. of Refs.: 3 | Attorney Docket No. | P71C2-US |

| U.S. PUBLISHED PATENT DOCUMENTS | | | | | | |
|---------------------------------|-----------------------|---|-------------------------------|-----------------|----------------------|----------------------------|
| Examiner Initials ^a | Cite No. ¹ | U.S. Patent Document Number Kind Code ² | Name of Patentee or Applicant | Publ/Issue Date | Related ³ | Copy Enclosed ⁴ |
| | 1. | 3806801 | Bove | 4/23/1974 | | No ^{***} |

| OTHER PRIOR ART – NONPATENT LITERATURE DOCUMENTS | | | | | | |
|--|-----------------------|--|--|--|----------------|---------------|
| Examiner Initials ^a | Cite No. ¹ | Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published | | | T ² | Copy Enclosed |
| | 2. | Taber et al. "Vertical Probing Experiences," International SEMATECH Wafer Probe Council, 2003 Southwest Test Workshop (2003) 29 pages | | | | Yes |
| | 3. | Mann, "'Leading Edge' Of Wafer Level Testing," 2004 Southwest Test Workshop (2004) 64 pages | | | | Yes |

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|--------------------|---------------------|-----------------|------------|
| Examiner Signature | /Ernest F. Karlson/ | Date Considered | 08/26/2009 |
|--------------------|---------------------|-----------------|------------|

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication

¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

** Reference cited in parent application US Serial No. _____, CFR § 1.98(d)

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& Notice dated October 19, 2004 by Deputy Commissioner for Patent Examination Policy waiving requirement to file copies of pending US patent applications if the applications are stored in the USPTO's IFW system.

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